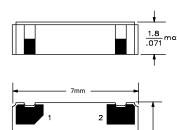


# 3.3V CMOS Low Jitter, High Frequency **Crystal Clock Oscillator (XO)**

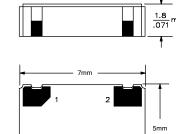




### **Packaging Outline**



Pin Functions		
Pin	Function	
1	<b>OE</b> Function	
2	Ground	
3	Clock Output	
4	VDD	

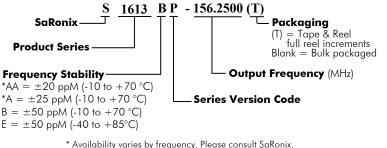


# **Common Frequencies**

Contact SaRonix for additional frequencies

100.0000 MHz	150.0000 MHz
106.2500 MHz	155.5200 MHz
125.0000 MHz	156.2500 MHz
127.0000 MHz	159.3750 MHz
133.0000 MHz	

# **Ordering Information**



# Actual Size $= 5 \times 7$ mm



### **Product Features**

- Thicker crystal for improved reliability
- Less than 1 ps RMS jitter with advanced non-PLL, patent-pending design
- $\pm$ 50ppM accuracy (all rated conditions including aging) standard for commercial or industrial operating conditions
- 3.3V CMOS/TTL compatible logic levels
- Pin-compatible with standard 5x7mm packages
- Designed for standard reflow and washing techniques
- IBIS model available •
- Pb-free and RoHS/Green compliant\*\* ٠ (\*\*per #7, Annex of Directive 2002/05/EC)

# **Product Description**

The S1613XP Series is an enhanced high-frequency version of the popular \$1613 series, a 3.3V crystal clock oscillator that achieves superb jitter and stability over a broad range of operating conditions and frequencies. The output clock signal, generated internally with a non-PLL oscillator design, is compatible with LVCMOS/LVTTL logic levels. The device, available on tape and reel, is contained in a 5x7mm surface-mount ceramic package.

# **Applications**

The S1613XP Series is an ideal reference clock for highspeed applications requiring low jitter, including:

- 1/10 Gigabit Ethernet
- FibreChannel •
- Serial Attached SCSI (SAS)
- Server & Storage platforms
- SONET/SDH linecards





# 3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

#### **Electrical Performance**

Parameter	Min.	Тур.	Max.	Units	Notes
Output frequency	100		160	MHz	As specified
Supply voltage	+2.97	+3.3	+3.63	V	
Supply current, output enabled			30	mA	
Supply current, output disabled			10	mA	Output Hi-Z
Frequency stability			±20 to ±50	ррМ	See Note 1 below
Operating temperature	-40		+85	°C	As specified
Output logic 0, VOL			10% V <sub>DD</sub>	V	
Output logic 1, VOH	90% V <sub>DD</sub>			V	
Output load	15 pF (max) or 10 LSTTL			TL	
Duty cycle	45		55	%	-10 to +70°C measured 50%VDD
Duty cycle	40		60	%	-40 to -10°C, +70 to +85°C measured 50%VDD
Rise and fall time			2	ns	measured 20/80% of waveform
Jitter, phase		0.25	1	ps RMS (1-σ)	12kHz to 40MHz frequency band
Jitter, accumulated			7	ps RMS (1-σ)	20,000 adjacent periods
Jitter, total			40	ps pk-pk	100,000 random periods
Subharmonic Level			-40	dBc	

#### Notes:

1. As specified. Stability includes all combinations of operating temperature, load changes, rated input (supply) voltage changes, initial calibration tolerance (25°C), aging (1 year at 25°C average effective ambient temperature), shock and vibration.

Sulput Enable / Disable Function					
Parameter	Min.	Тур.	Max.	Units	Notes
Input Voltage (pin 1), Output Enable	2.2			V	or open
Input voltage (pin 1), Output Disable			0.8	V	Output is Hi-Z
Internal pullup resistance	50			kΩ	
Output disable delay			100	ns	
Output enable delay			1	ms	

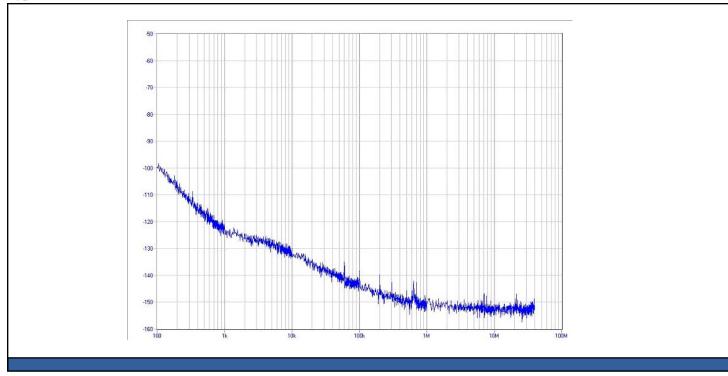
#### **Output Enable / Disable Function**



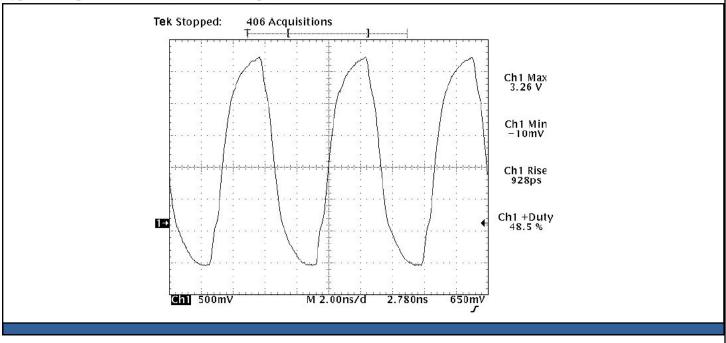


# 3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

#### **Typical Phase Noise**



#### **Typical Output Waveform (150 MHz output)**



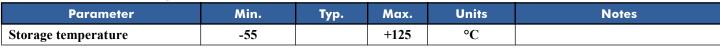
All specifications are subject to change without notice. DS 263 Rev B | 08/19/05



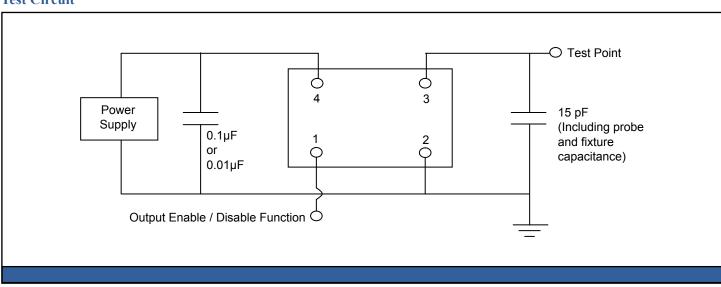


# 3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

#### **Absolute Maximum Ratings**



## **Test Circuit**



## **Reliability Test Ratings**

This product is rated to meet the following test conditions:

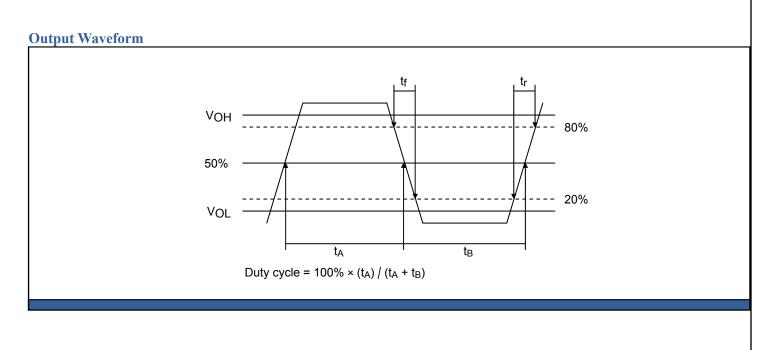
Туре	Parameter	Test Condition
Mechanical	Shock	MIL-STD-883, Method 2002, Condition B
Mechanical	Solderability	JESD22-B102-D Method 2 (Preconditioning E)
Mechanical	Terminal strength	MIL-STD-883, Method 2004, Condition D
Mechanical	Gross leak	MIL-STD-883, Method 1014, Condition C
Mechanical	Fine leak	MIL-STD-883, Method 1014, Condition A2 ( $R_1 = 2x10^{-8}$ atm cc/s)
Mechanical	Solvent resistance	MIL-STD-202, Method 215
Environmental	Thermal shock	MIL-STD-883, Method 1011, Condition A
Environmental	Moisture resistance	MIL-STD-883, Method 1004
Environmental	Vibration	MIL-STD-883, Method 2007, Condition A
Environmental	Resistance to soldering heat	J-STD-020C Table 5-2 Pb-free devices (2 cycles max)



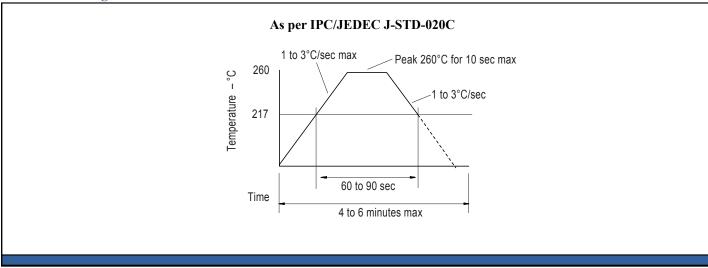
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# 3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)



### **Reflow Soldering Profile**



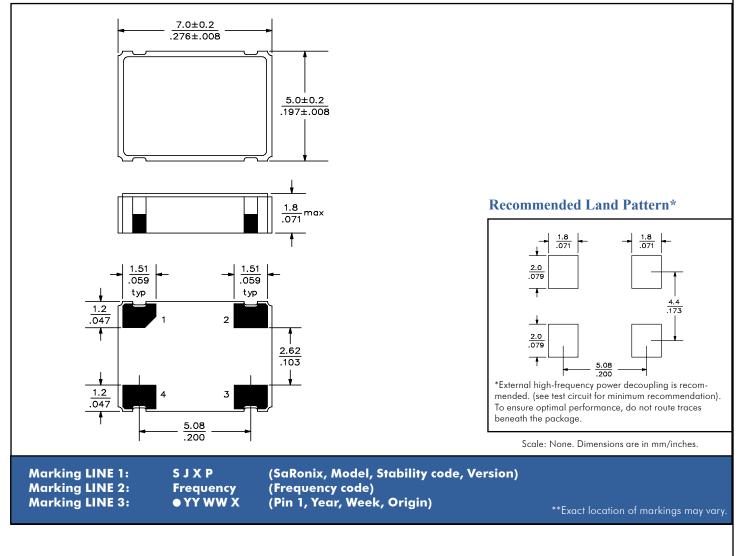
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# 3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

### **Mechanical Drawings**



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